

Search Notes

Application/Control No.

10/032,036

Examiner

James K. Trujillo

Applicant(s)/Patent under
Reexamination

LIN ET AL.

Art Unit

2116

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|-----------------------------|-----------|----------|
| 713 | 300,320, 322,323, 324 | 3/21/2005 | JKT |
| 345 | 173 | 3/21/2005 | JKT |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| Databases Searched: East NPL: IEEE, ACM see attached. | 3/21/2005 | JKT |
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